

Abstract Submitted  
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**High mobility Single Layer Epitaxial Graphene on 4H-SiC (000-1)**

YIKE HU, ZELEI GUO, MING RUAN, JOHN HANKINSON, JAMES PALMER, BAIQIAN ZHANG, RUI DONG, JAN KUNC, CLAIRE BERGER, WALT DEHEER, Georgia Institute of Technology — Multi-layer Epitaxial Graphene on 4H-SiC (000-1) has demonstrated very high mobility up to  $\sim 27,000 \text{ cm}^2/\text{Vs}$  [1]. Recently single layer graphene grown by the Confinement Control Growth method [2] exhibits mobility up to  $\sim 25,000 \text{ cm}^2/\text{V}\cdot\text{s}$  at 4K and  $13,000 \text{ cm}^2/\text{V}\cdot\text{s}$  at 300K with  $p=3 \times 10^{12} \text{ cm}^{-2}$ . The relation between Raman G peak features (FWHM and position) and carrier density of Epitaxial Graphene on carbon face is revealed. Quantum Hall Effect [3] is observed both for p and n type carriers on top gated sample. This indicates that top gated single layer graphene can be produced on the Carbon face with high quality and high carrier mobility.

[1] Science **312**, 1191 (2006)

[2] PNAS **108** (41) 16900 (2011)

[3] APL **95**, 223108 (2009)

Yike Hu  
Georgia Institute of Technology

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